



DME - Danish Micro Engineering A/S

DME Nanotechnologie GmbH

<http://www.dme-spm.com>

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Since 1987 manufacturer of
Scanning Probe Microscopes

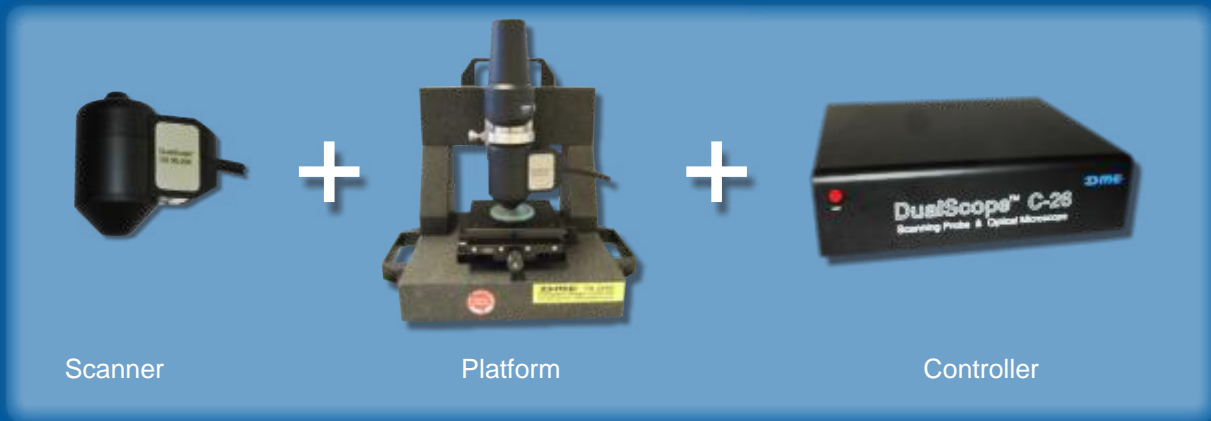
DME DS 95 AFM Scanner



- Two standard sizes:
50 x 50 x 5 μm and 200 x 200 x 15 μm , both scanners show atomic surface layers
- Compact probe scanner, the cantilever moves during scanning, not the sample
- Can be operated in any orientation
- No need of a special sample holder
- Supports most AFM modes without additional add-ons
- Built-in microscope objective for rough positioning
- Fully automatic laser alignment
- Foolproof cantilever change within seconds
- Z-linearization
- Can be mounted in a wide range of different platforms



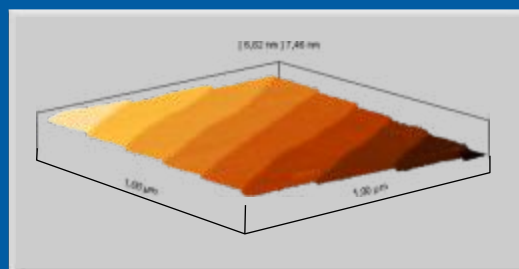
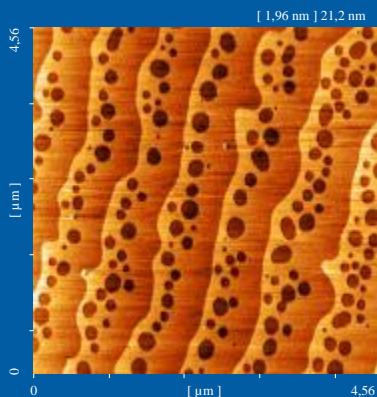
Assemble your individual AFM setup by choosing between different combination possibilities, depending on the type of application and desired degree of automation.



DME AFM-System

Benefit from our long experience and take a decision for one of the most productive AFM systems. Our instruments are very easy to use and work unbeatably fast and stable. This is among other things supported by following features, all our AFMs have:

- Fully automatic and extremely soft cantilever approach
- Cantilever surveillance functions that make your cantilever last longer, also when working with rough samples
- Fully automatic frequency adjustment and oscillation surveillance
- Automatic adaptive resolution control, so that you reach atomic resolution even with our largest scanner
- Active cantilever resonance feedback for lower interaction forces at difficult measurement conditions (e.g. liquid media)
- High built-in stability, commonly obtain atomic resolution just on a normal desktop without additional vibration isolation



Both scans: atomically resolved steps of SrTiO₃ samples, scanned with a DS 95-50 scanner at "Institut für elektrische Messtechnik", TU Braunschweig, Germany



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<http://www.dme-spm.com>
Copenhagen
Denmark